International Rectifier

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

Description

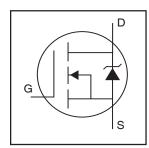
Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

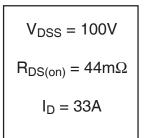
The D²Pak is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible onresistance in any existing surface mount package. The D²Pak is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.

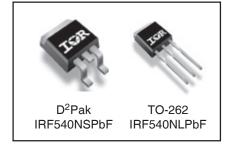
The through-hole version (IRF540NL) is available for low-profile applications.

IRF540NSPbF IRF540NLPbF

HEXFET® Power MOSFET







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V ⑦	33	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V ⑦	23	Α
I _{DM}	Pulsed Drain Current ①⑦	110	
P _D @T _C = 25°C	Power Dissipation	130	W
	Linear Derating Factor	0.87	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
I _{AR}	Avalanche Current①	16	А
E _{AR}	Repetitive Avalanche Energy①	13	mJ
dv/dt	Peak Diode Recovery dv/dt ③⑦	7.0	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.15	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mount)**		40	O/ VV

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.12		V/°C	Reference to 25°C, I _D = 1mA ⑦
R _{DS(on)}	Static Drain-to-Source On-Resistance			44	mΩ	V _{GS} = 10V, I _D = 16A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
9fs	Forward Transconductance	21			S	V _{DS} = 50V, I _D = 16A⊕⑦
I _{DSS}	Drain-to-Source Leakage Current			25	μA	V _{DS} = 100V, V _{GS} = 0V
צפטי	Brain to Godice Leakage Guiterit			250	μΛ	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	''^	V _{GS} = -20V
Qg	Total Gate Charge			71		I _D = 16A
Q _{gs}	Gate-to-Source Charge			14	nC	$V_{DS} = 80V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			21		V _{GS} = 10V, See Fig. 6 and 13 ④⑦
t _{d(on)}	Turn-On Delay Time		11			$V_{DD} = 50V$
t _r	Rise Time		35		no	$I_D = 16A$
t _{d(off)}	Turn-Off Delay Time		39		ns	$R_G = 5.1\Omega$
t _f	Fall Time		35			V _{GS} = 10V, See Fig. 10 ⊕⑦
1	Internal Drain Inductance		4.5			Between lead,
L _D	Internal Dialit inductance				nH	6mm (0.25in.)
L _S	Internal Source Inductance		7.5		ПП	from package
						and center of die contact
C _{iss}	Input Capacitance		1960			V _{GS} = 0V
Coss	Output Capacitance		250			$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		40		pF	$f = 1.0 \text{MHz}$, See Fig. 5 \bigcirc
E _{AS}	Single Pulse Avalanche Energy 27		700⑤	185©	mJ	I _{AS} = 16A, L = 1.5mH

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions							
Is	Continuous Source Current		20		MOSFET symbol								
	(Body Diode)		33	Α	showing the								
I _{SM}	Pulsed Source Current					_		- 110	110	110	110		integral reverse
	(Body Diode)①						110				p-n junction diode.		
V _{SD}	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C$, $I_S = 16A$, $V_{GS} = 0V$ ④							
t _{rr}	Reverse Recovery Time		115	170	ns	$T_J = 25^{\circ}C, I_F = 16A$							
Q _{rr}	Reverse Recovery Charge		505	760	nC	di/dt = 100A/µs ④⑦							
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)											

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\label{eq:starting} \begin{array}{ll} \text{ \ensuremath{\mathbb{Q}} Starting T_J = 25°C, L =1.5mH} \\ R_G = 25\Omega, I_{AS} = 16\text{A}. \ensuremath{\text{(See Figure 12)}} \end{array}$
- $\label{eq:loss} \begin{array}{l} \text{ } \exists \text{ } I_{SD} \leq 16\text{A, di/dt} \leq 340\text{A/}\mu\text{s, } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}\text{C} \end{array}$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- $\mbox{\ensuremath{\mbox{\ensuremath}\ensuremat$
- ② Uses IRF540N data and test conditions.
- **When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994

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IRF540NS/LPbF

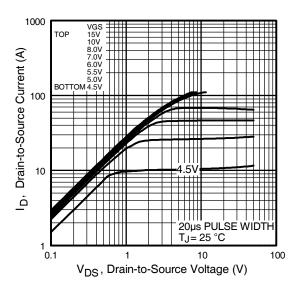


Fig 1. Typical Output Characteristics

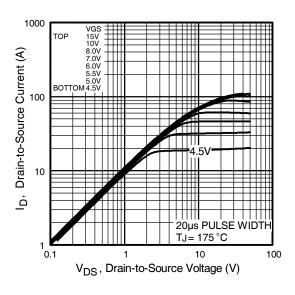


Fig 2. Typical Output Characteristics

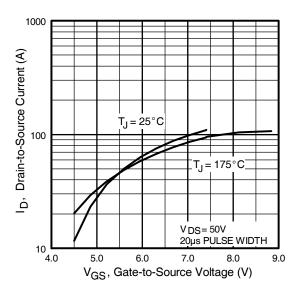


Fig 3. Typical Transfer Characteristics

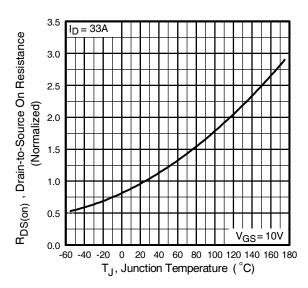


Fig 4. Normalized On-Resistance Vs. Temperature

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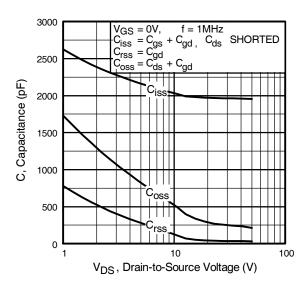


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

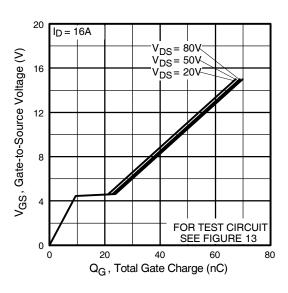


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

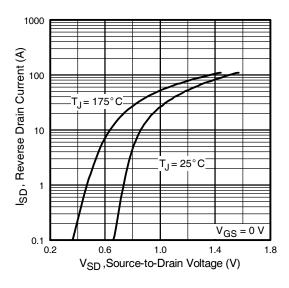


Fig 7. Typical Source-Drain Diode Forward Voltage

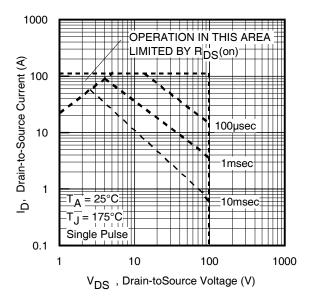


Fig 8. Maximum Safe Operating Area www.irf.com

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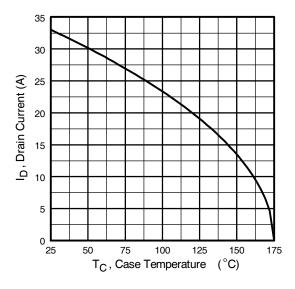


Fig 9. Maximum Drain Current Vs. Case Temperature

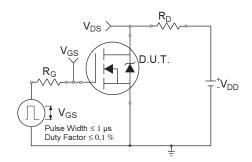


Fig 10a. Switching Time Test Circuit

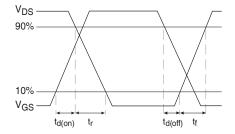


Fig 10b. Switching Time Waveforms

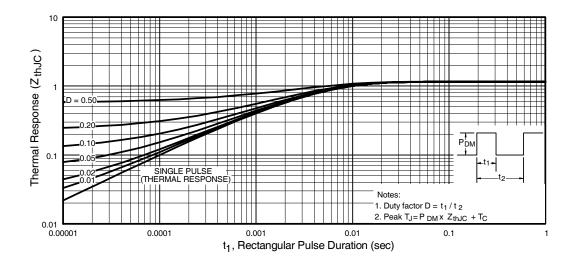


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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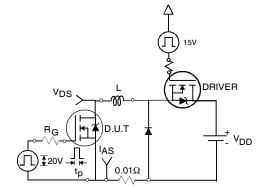


Fig 12a. Unclamped Inductive Test Circuit

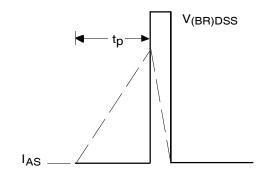


Fig 12b. Unclamped Inductive Waveforms

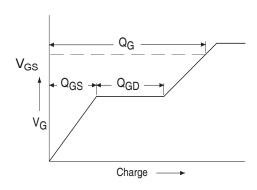


Fig 13a. Basic Gate Charge Waveform

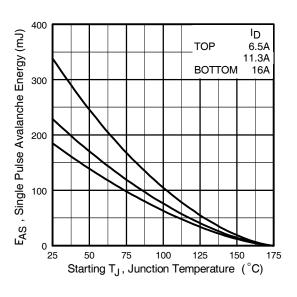


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

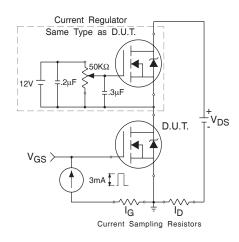
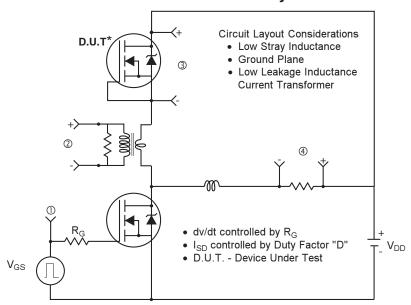
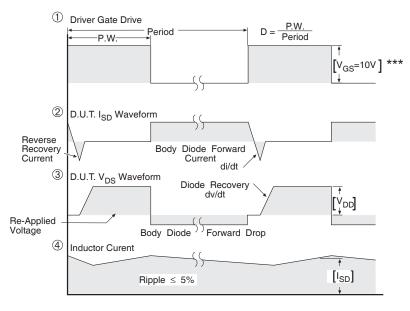


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel

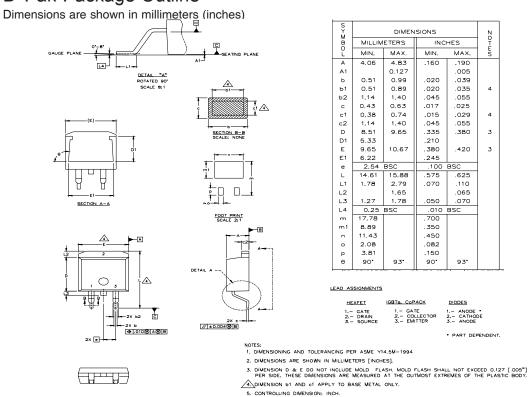


*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

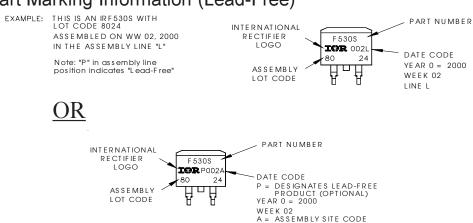
Fig 14. For N-channel HEXFET® power MOSFETs

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D²Pak Package Outline



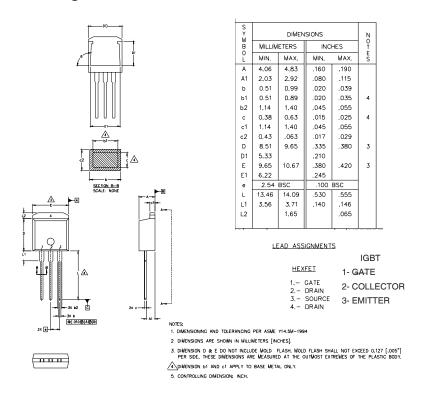
D²Pak Part Marking Information (Lead-Free)



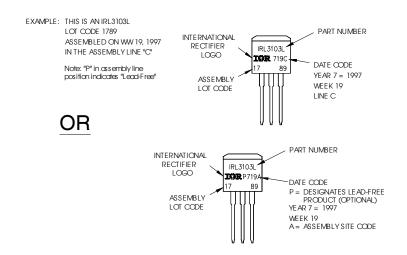
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IRF540NS/LPbF

TO-262 Package Outline

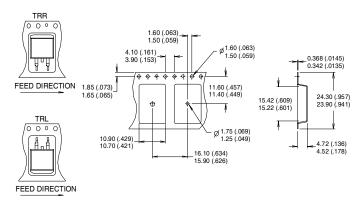


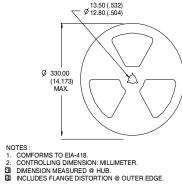
TO-262 Part Marking Information

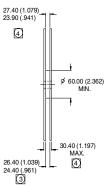


D²Pak Tape & Reel Infomation

Dimensions are shown in millimeters (inches)







Data and specifications subject to change without notice. This product has been designed and qualified for the industrial market. Qualification Standards can be found on IR's Web site.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/